

Application/Control No.	Applicant(s)/Patent under Reexamination
10/064,251	LI ET AL.
Examiner	Art Unit
HABTE MERED	2416

SEARCHED				
Class	Subclass	Date	Examiner	
370	221-223	10/11/2008	НМ	
370	216-218	10/11/2008	НМ	
370	225,227	10/11/2008	НМ	
370	228	10/11/2008	НМ	
370	241,242	10/11/2008	НМ	
370	244	10/11/2008	НМ	
370	250,400	10/11/2008	НМ	
370	401,406	10/11/2008	НМ	
714	100,1,2	10/11/2008	НМ	
709	239	10/11/2008	НМ	
379	221.1	10/11/2008	НМ	
379	221.04	10/11/2008	НМ	

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
	Subclass	Subclass Date			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched East DB:USPAT, UPGPUB, JPO, EPO	10/11/2008	НМ		
IEEE	10/11/2008	НМ		
Palm Inventor's DB	10/11/2008	НМ		
Consulted John Pezzlo (Primary) on search strategy and rejection strategy	8/24/2007	НМ		
Consulted Doris (SPE) To on srejection strategy	8/28/2007	НМ		
Consulted A. Moe (SPE) on allowable subject matter and rejection strategies	10/10/2008	НМ		